

<b>Notice of References Cited</b>	Application/Control No. 10/579,418	Applicant(s)/Patent Under Reexamination STEK ET AL.	
	Examiner Phuong Huynh	Art Unit 2857	Page 1 of 1

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*	B	US-5,677,686	10-1997	Kachi et al.	341/8
*	C	US-5,663,643	09-1997	Matuyama, Yasuhiko	324/207.12
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**NON-PATENT DOCUMENTS**

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